


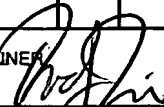
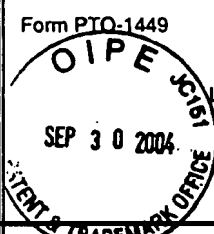




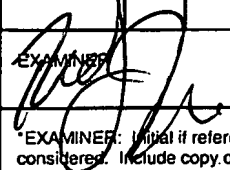
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1940	SERIAL NO. 10/087,558		
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT: Micron Technology, Inc.			
				FILING DATE February 28, 2002	GROUP 1763		
U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
 	AA	2003/0003697A1	01-2003	Agarwal et al.		Aug. 21, 2002	
	AB	2003/0001190A1	01-2003	Basceri et al.		Aug. 26, 2002	
	AC	2002/0037630A1	03-2002	Agarwal et al.		Oct. 29, 2001	
	AD	6,787,185 B2	09-2004	Derderian et al.			
	AE	6,765,250 B2	07-2004	Doan et al.			
	AF	6,746,934 B2	06-2004	Sandhu et al.			
	AG	6,689,624 B2	02-2004	Doan et al.			
	AH	6,653,154 B2	11-2003	Doan et al.			
	AI	6,627,260 B2	09-2003	Derderian et al.			
FOREIGN PATENT DOCUMENTS							
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				FILING DATE February 28, 2002	GROUP 1763	
U.S. PATENT DOCUMENTS						
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
MA	6,596,636 B2	07-2003	Sandhu et al.			
AB	6,596,583 B2	07-2003	Agarwal et al.			
AC	6,559,472 B2	05-2003	Sandhu et al.			
AD	6,541,353 B1	04-2003	Sandhu et al.			
AE	6,534,357 B1	03-2003	Basceri et al.			
AF	6,458,416 B1	10-2002	Derderian et al.			
AG	6,420,230 B1	07-2002	Derderian et al.			
AH	5,463,978	11-1995	Larkin et al.			
AI	6,143,659	11-2000	Leem			
FOREIGN PATENT DOCUMENTS						
Document Number	Date	Country	Class	Subclass	Translation	
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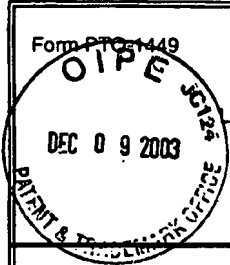
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U.S. PATENT DOCUMENTS							
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	AA	6,478,872 B1	11-2002	Chae et al.			
	AB						
	AC						
	AD						
	AE						
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	AG						
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FOREIGN PATENT DOCUMENTS							
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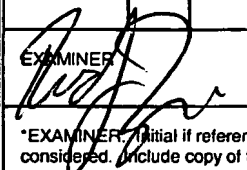
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FILING DATE February 28, 2002				GROUP 1763			

U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	AA	6,185,839 B1	02/2001	Kholodenko et al.	34	255	
	AB	6,245,151 B1	06/2001	Bhandari et al.	34	255	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Ross S. Dando et al.				
				FILING DATE February 28, 2002		GROUP 1763		
U.S. PATENT DOCUMENTS								
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
	AA	5,620,524	04/15/97	Fan et al.				
	AB	6,419,462 B1	07/16/02	Horie et al.				
	AC							
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	AF							
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Patent and Trademark Office

Attorney Docket Number
9281.7

Serial No.
10/087,548

LIST OF DOCUMENTS CITED BY APPLICANT

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Applicants:

Shefet et al.

Filing Date
March 1, 2002

Group
3743

U. S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>AS</i>	1.	4,726,766	02/1988	Stewart et al.	432	133	
<i>AS</i>	2.	5,843,504	12/1998	Kobussen et al.	426	277	

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FOREIGN PATENT DOCUMENTS

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<i>AS</i>	2.	5,843,504	12/1998	Kobussen et al.	426	277	

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